



SEMI®  
International  
Standards



semi™

Semiconductor Equipment and Materials International

## SEMI International Standards Program

PV - Automation Committee Europe

### PV Wafer Traceability Task Force

#### 4<sup>th</sup> Meeting

January 17th 2011, 10:30 – 16:00 (MET)

**InnoLas Systems GmbH (Amman Gebäude); Konrad Zuse Bogen 19; 82152 Krailling**

SEMI Staff contact: Carlos Lee, Mobile: +32 473 300433

### Agenda

**Objective of the Meeting:** Preparation of ballot for standard proposal “Specification for Marking of PV Wafer”

**Co-chairs:** István Győry / Innovation Engineering & Services GmbH. (IE&S)  
Andreas Behr / InnoLas GmbH

**Coaching:** Gerhard Kleineidam / InReCon AG  
SEMI Europe Regional Standards Committee Advisor

10:30	Welcome and Introductions	István Győry, all
10:45	SEMI Reminders and Basic Rules	Gerhard Kleineidam
11:00	Agenda and TF goals	István Győry
11:15	Decisions and open points	István Győry
11:30	Marking bricks on the side with barcode	Jürgen Grosser
11:50	Traceability from the perspective of the wafer manufacturer	Kristian Helland
12:10	Test results matrix marking From the marking perspective From the reading perspective From the cell production perspective	Andreas Behr / Richard Hendel Joachim Gässler/ Walter Braitsch Uli vom Bauer
13:00	Coffee break	all
14:00	Brain storming	all
15:00	Decisions open Points	all
15:15	Next Steps	István Győry
15:30	Adjourn	